# Cascade

# PA200/AP200 BlueRay

Fastest Production Testing Without Compromising Accuracy

Operation lamp for machine status

Instrument shelf for easy access to measurement equipment

### Microscope

• High-resolution optics for probe inspection, wafer navigation and alignment

### Universal platen setup

• For use with DC and RF positioners and probe cards

### Base machine

- 200 mm x/y stage for reliable 24/7 operations
- · Low maintenance
- Designed for fast die stepping up to 10 die/sec
- High-accuracy Z-stage for minimum scrub mark

# Chuck

- Conductive chuck surface with vacuum holes for thin wafers
- Integrated AUX sites for calibration and cleaning sites
- Thermal test capability (25° C to 150° C)

### Integrated vibration isolation system

- Eliminates vibration from external sources (acoustic, architectural, etc.)
- Enhances system stability
- Reduces damage to pads, wafers and probe tips

### Small footprint machine table

- Integrates all prober components and supplies
- Integrated rollers

### **Electronics box**

- Stable. Linux-based controller
- Realtime PID motion controller
- Z-Profiling: Automatic wafer warpage compensation
- $\bullet$  Integrated, reliable industrial PC for running Velox probe station control software

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# Velox<sup>™</sup> probe station control software

- Operate machine in a semi-automatic engineering mode
- Free die-to-die navigation on wafer
- Individual die testing

### VeloxPro™ test automation software

- Easy-to-use SEMI E95 compliant user interface
- Efficient communication with test executive software
- Powerful pattern recognition capability

### Expert control panel

- Comfortable use without PC
- Full control of all probe stages with position feedback
- Entire system control from one panel
- Analog joystick for precise, sub-micron positioning
- Point-and-shoot navigation

### Loader module

- Universal cassette stand for substrates from 2" to 8"
- Integrated pre-aligner for flat/notch detection
- Barcode/2D matrix code/OCR wafer code recognition
- Field upgradeable

# PA200DS BlueRay

### Chuck for double-sided substrates

# Measurement instrumentation

• Prepared for 4" integrating sphere, fiber optics



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